Electronic Supplementary Material (ESI) for CrystEngComm

On the crystallization of Ta_2O_5 nanotubes: Structural and local atomic properties investigated by EXAFS and XRD

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Supplementary Figures

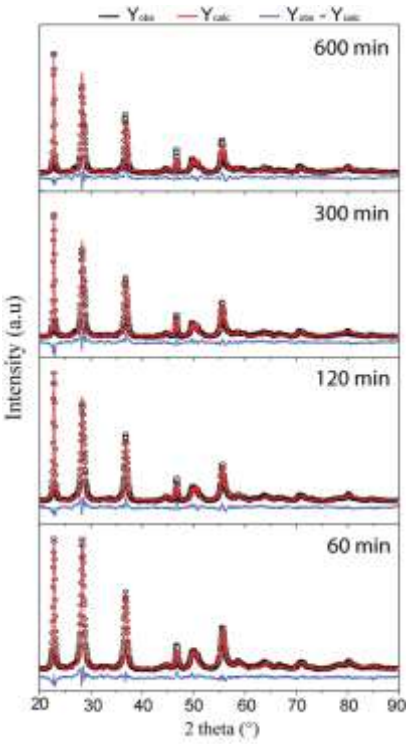

Figure S1. XRD diffractograms of the Ta_2O_5 NTs annealed at 800 °C for 60, 120, 300 and 600 min.

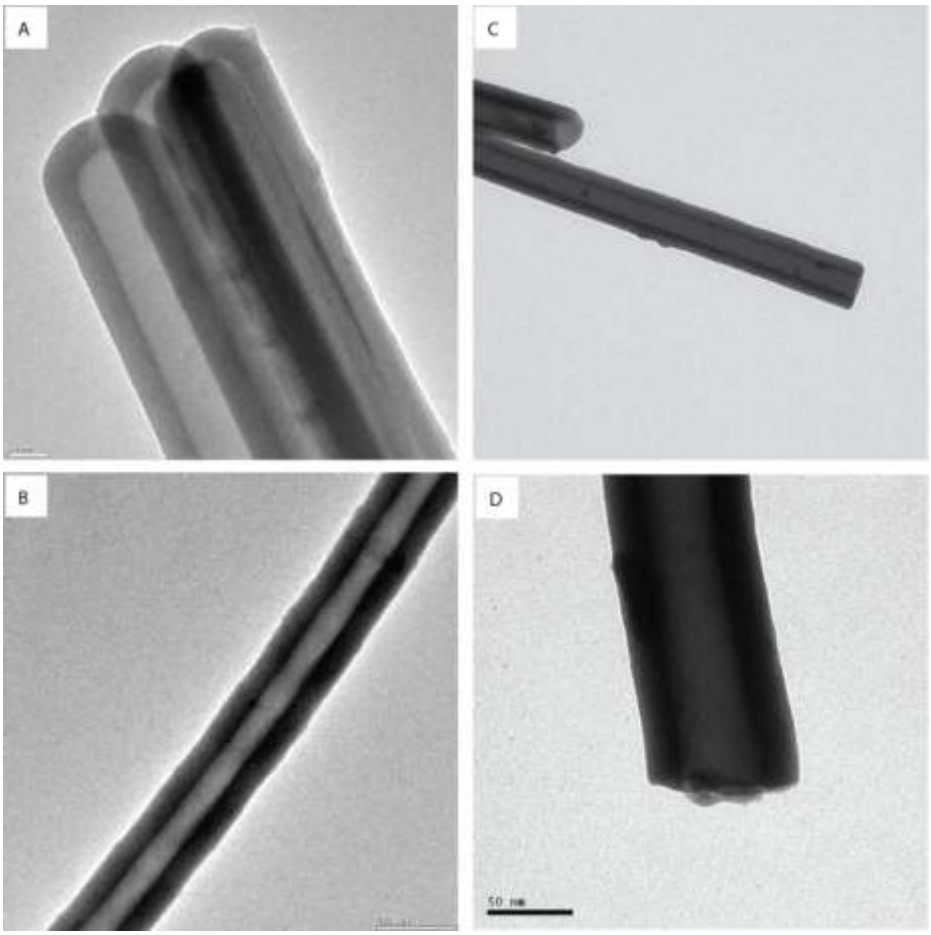

Figure S2. TEM images: A and B are amorphous Ta_2O_5 NTs and C and D are NTs annealed at 800 °C for 30 min.

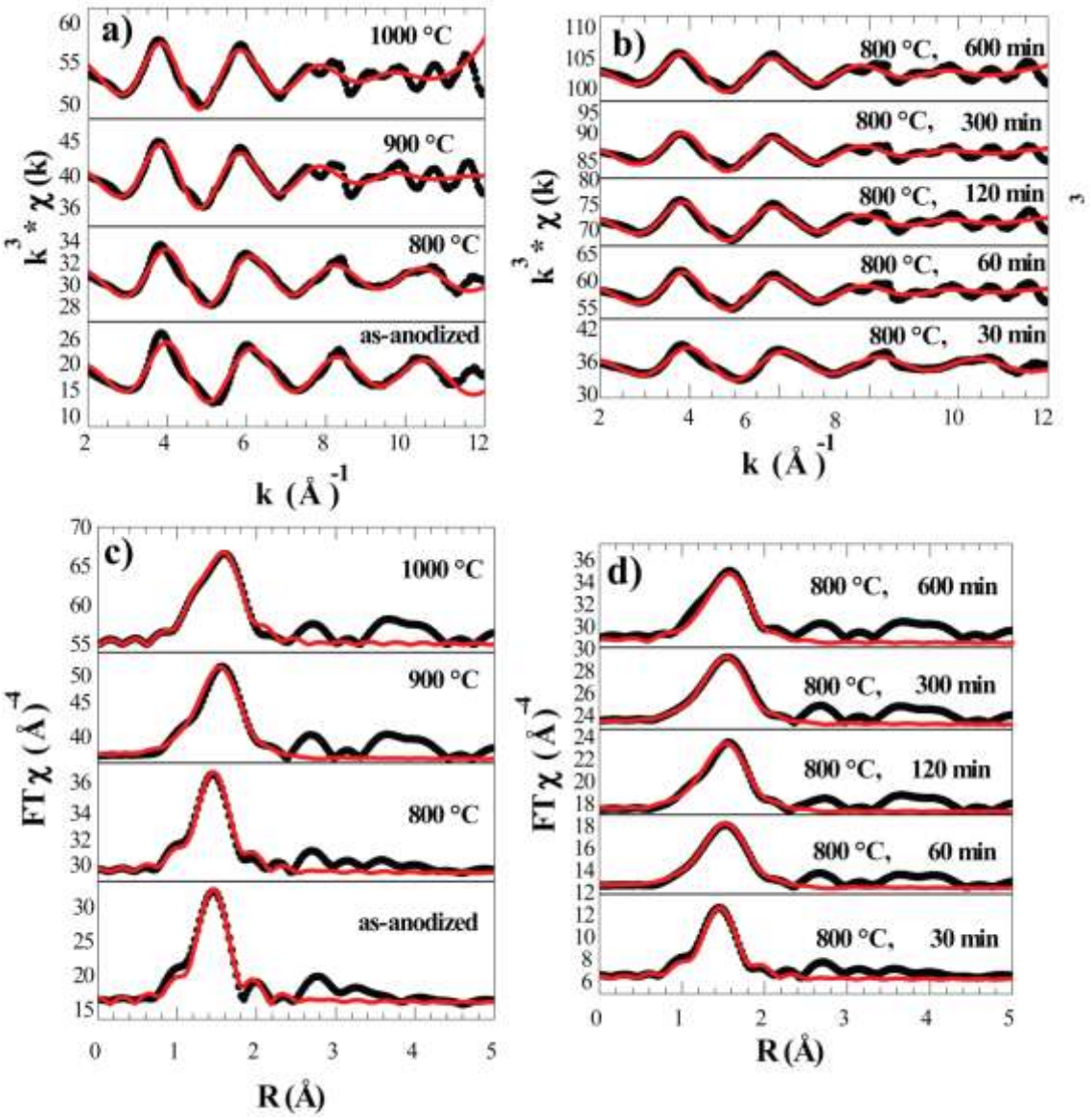

Figure S3. (a, b) k^3-weighted Ta L_3 EXAFS signal and (c, d) the corresponding Fourier transform magnitude. Red lines represent the best fits obtained.